PCN# : P662AAB
Issue Date : Nov. 01, 2016

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local ON Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples.

Implementation of change:

Expected First Shipment Date for Changed Product :Jan. 30, 2017

Expected First Date Code of Changed Product :1706

Description of Change (From) :
Sort Site: ON Semiconductor Bucheon, Korea
Sort Site: ON Semiconductor Cebu, Philippines
Sort Site: ON Semiconductor Mountain Top, USA
Sort Site: ON Semiconductor Suzhou, China

Description of Change (To) :
Sort Site: ON Semiconductor Bucheon, Korea

Reason for Change:
. To consolidate Sort Operations from Cebu, Mountain Top and Suzhou to Bucheon
. One standard practice for Operations

Affected Product(s):

4E85_BSS84	G785_BSS123	PCF045AN08W_R4800
PCF2532W_R4800	PCF332PW	PCF33468
PCF430NZW	PCF430NZW_SN00383	PCF457NW
PCF6294W	PCF75307W_R4903	PCF75337D_SN00209
PCF75337W_S2496	PCF76129W	PCF8672SW
PCF8896W	PCFA33468D	PCFA75545W
PCFA82769W	PCFD031N08W	PCFD8870W
PCGA3040G2F	PCGA3056W	PCGA49451F
PCGA49452D	PCGA49452W	PCGA49455W
PCRA49560W		

Qualification Plan: ON Cebu to ON Bucheon

- Equipment : Tester(ETS200T) 1set & prober station(P8XL) 1set (same machine/probe card)
- Product : T5XGEAZ08TNST_TJAA
- Overall yield variance: 0.01% vs Criteria <=0.5%
- Test Program Control Request Number: TPCR-029796

Site	Lot No	Wafers	Yield	Remark
Cebu	ET600535	1wafer (#24)	99.77%	Sending Site
Bucheon	PW006567BK	1wafer (#24)	99.76%	Receiving Site

- Equipment : Tester(ETS200T Common Drain) 1set & prober station(P8XL) 1set (same machine/probe card)
- Product : RI02AMZ8TNSA8_VA
- Overall yield variance: 0.4% vs Criteria <=0.5%
- Test Program Control Request Number: TPCR-030514

Site	Lot No	Wafers	Yield	Remark
Cebu	PW00061358	1wafer (#18)	83.90%	Sending Site
Bucheon	H0F450BK	1wafer (#18)	84.30%	Receiving Site

Qualification Plan: ON Suzhou to ON Bucheon

- Equipment : Tester(ETS200T) 1set & prober station(P8XL) 1set (same machine/probe card)
- Product : 33478DNJ, PT4
- Overall yield variance: 0.04% vs Criteria <=0.5%
- Test Program Control Request Number: TPCR-029468

Site	Lot No	Wafers	Yield	Remark
Suzhou	XW00021526	3wafers (#14~16)	94.71%	Sending Site
Bucheon	XW021526BK	3wafers (#14~16)	94.75%	Receiving Site

Qualification Plan: ON Mountain Top to ON Bucheon

- Equipment : Tester(ETS200T) 1set & prober station(P8XL) 1set (same machine/probe card)
- Product : 49560LRJB
- Overall yield variance: 0.06% vs Criteria <=0.5%
- Test Program Control Request Number: TPCR-031401

Site	Lot No	Wafers	Yield	Remark
Mountain Top	LJ7DXCB	3wafers(#23,#24,#25)	98.66%	Sending Site
Bucheon	LJ7DXBKH	3wafers (#23,#24,#25)	98.60%	Receiving Site